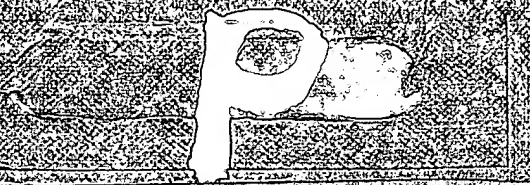


Class	Subclass

ISSUE CLASSIFICATION



PATENT NUMBER

# U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
<i>11/17/92</i>	<i>01/11/93</i>

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/870702	D F	430	5	1756	<i>Mohamedally</i>

APPLICANTS

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TITLE

Method for repairing a photomask, method for inspecting a photomask, method for manufacturing a photomask, and method for manufacturing a semiconductor device

PTO-6040  
12/89

## ISSUING CLASSIFICATION

CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER CLASS)

☐ Continued on back of this application

## DRAWINGS

Sheet 1 of 1	First Sheet	Print File	Text File	Figure File
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<p>NOTE: IF MULTIPLE SHEETS ARE SUBMITTED, THE FIRST SHEET MUST BE THE FIRST SHEET OF THE APPLICATION.</p> <p>ISSUE DATE</p> <p>Amount Due</p>	<p>NOTE: IF MULTIPLE SHEETS ARE SUBMITTED, THE FIRST SHEET MUST BE THE FIRST SHEET OF THE APPLICATION.</p> <p>ISSUE DATE</p> <p>Amount Due</p>
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☒ The terminal 12 months of this patent have been designated.

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Form PTO-6040  
(Rev. 8/89)

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